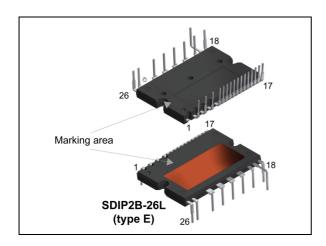


### STGIB15CH60TS-E

SLLIMM<sup>™</sup> - 2<sup>nd</sup> series IPM, 3-phase inverter, 20 A, 600 V short-circuit rugged IGBTs

Datasheet - production data



#### **Features**

- IPM 20 A, 600 V 3-phase IGBT inverter bridge including 2 control ICs for gate driving and freewheeling diodes
- 3.3 V, 5 V TTL/CMOS inputs with hysteresis
- Internal bootstrap diode
- Undervoltage lockout of gate drivers
- Smart shutdown function
- Short-circuit protection
- Shutdown input/fault output
- Separate open emitter outputs
- Built-in temperature sensor
- Comparator for fault protection
- Short-circuit rugged TFS IGBTs
- Very fast, soft recovery diodes
- 85 kΩ NTC UL 1434 CA 4 recognized
- Fully isolated package
- Isolation rating of 1500 Vrms/min

### **Applications**

- · 3-phase inverters for motor drives
- Home appliances such as washing machines, refrigerators, air conditioners and sewing machines

### **Description**

This second series of SLLIMM (small low-loss intelligent molded module) provides a compact, high performance AC motor drive in a simple, rugged design. It combines new ST proprietary control ICs (one LS and one HS driver) with an improved short-circuit rugged trench gate field-stop (TFS) IGBT, making it ideal for 3-phase inverter systems such as home appliances and air conditioners. SLLIMM<sup>™</sup> is a trademark of STMicroelectronics.

Table 1. Device summary

Order code	Marking	Package	Packaging
STGIB15CH60TS-E	GIB15CH60TS-E	SDIP2B-26L	Tube

September 2015 DocID026590 Rev 4 1/25

Contents STGIB15CH60TS-E

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## 1 Internal schematic and pin description

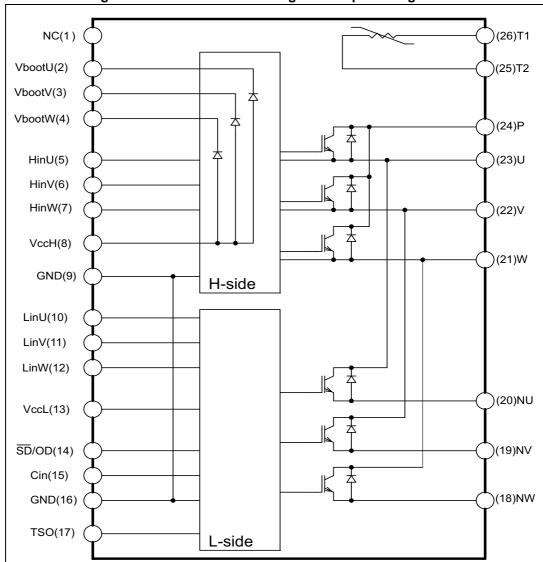


Figure 1. Internal schematic diagram and pin configuration

Table 2. Pin description

Pin	Symbol	Description
1	NC	-
2	VBOOTu	Bootstrap voltage for U phase
3	VBOOTv	Bootstrap voltage for V phase
4	VBOOTw	Bootstrap voltage for W phase
5	HINu	High-side logic input for U phase
6	HINv	High-side logic input for V phase
7	HINw	High-side logic input for W phase
8	VCCH	High-side low voltage power supply
9	GND	Ground
10	LINu	Low-side logic input for U phase
11	LINv	Low-side logic input for V phase
12	LINw	Low-side logic input for W phase
13	VCCL	Low-side low voltage power supply
14	SD/OD	Shutdown logic input (active low) / open-drain (comparator output)
15	CIN	Comparator input
16	GND	Ground
17	TSO	Temperature sensor output
18	NW	Negative DC input for W phase
19	NV	Negative DC input for V phase
20	NU	Negative DC input for U phase
21	W	W phase output
22	V	V phase output
23	U	U phase output
24	Р	Positive DC input
25	T2	NTC thermistor terminal 2
26	T1	NTC thermistor terminal 1

# 2 Absolute maximum ratings

 $(T_i = 25$ °C unless otherwise noted).

Table 3. Inverter parts

Symbol	Symbol Parameter		Unit
V <sub>PN</sub>	V <sub>PN</sub> Supply voltage between P -N <sub>U</sub> , -N <sub>V</sub> , -N <sub>W</sub>		V
V <sub>PN(surge)</sub>	Supply voltage surge between P -N <sub>U</sub> , -N <sub>V</sub> , -N <sub>W</sub>	500	V
V <sub>CES</sub>			V
41.	Continuous collector current each IGBT (T <sub>C</sub> = 25 °C)	20	А
±l <sub>C</sub>	Continuous collector current each IGBT (T <sub>C</sub> = 80 °C)	15	A
±l <sub>CP</sub>	Peak collector current each IGBT (less than 1ms)	40	А
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> =25°C each IGBT	81	W
t <sub>scw</sub>	Short circuit withstand time, $V_{CE}$ = 300V, $T_{J}$ = 125 °C, $V_{CC}$ = $V_{boot}$ = 15 V, $V_{IN}$ = 0 to 5 V	5	μs

**Table 4. Control parts** 

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	Supply voltage between V <sub>CCH</sub> -GND, V <sub>CCL</sub> -GND		20	V
V <sub>BOOT</sub>	Bootstrap voltage	-0.3	619	V
V <sub>OUT</sub>	V <sub>OUT</sub> Output voltage between U, V, W and GND		V <sub>BOOT</sub> + 0.3	V
V <sub>CIN</sub>	V <sub>CIN</sub> Comparator input voltage		20	V
V <sub>IN</sub>	V <sub>IN</sub> Logic input voltage applied between HINx, LINx and GND		15	V
V <sub>SD</sub> /OD	Open drain voltage	-0.3	7	V
I <sub>SD</sub> /OD	I <sub>SD</sub> /OD Open drain sink current		10	mA
V <sub>TSO</sub> Temperature sensor output voltage		-0.3	5.5	V
I <sub>TSO</sub>	Temperature sensor output current		7	Α

Table 5. Total system

Symbol	ymbol Parameter		Unit
V <sub>ISO</sub>	Isolation withstand voltage applied between each pin and heat sink plate (AC voltage, t = 60sec.)	1500	Vrms
T <sub>J</sub>	Power chips operating junction temperature	-40 to 175	°C
T <sub>C</sub>	Module case operation temperature	-40 to 125	°C



### Table 6. Thermal data

Symbol	bol Parameter		Unit
D	Thermal resistance junction-case single IGBT	1.85	00/14/
K <sub>th(j-c)</sub>	Thermal resistance junction-case single diode	2.8	°C/W

### 3 Electrical characteristics

 $(T_i = 25$ °C unless otherwise noted).

Table 7. Inverter parts

Symbol	Parameter	Test condition	Min	Тур	Max	Unit
I <sub>CES</sub>	Collector-cut off current	V <sub>CE</sub> = 600 V, V <sub>CC</sub> = V <sub>boot</sub> = 15 V	-		100	μA
V	Collector-emitter	$V_{CC} = V_{Boot} = 15 \text{ V}, \ V_{IN}^{(1)} = 0 \text{ to 5 V}, \ I_{C} = 15 \text{ A},$		1.6	2.1	.,,
V <sub>CE(sat)</sub>	saturation voltage	$V_{CC} = V_{Boot} = 15 \text{ V}, V_{IN}^{(1)} = 0 \text{ to 5 V},$ $I_{C} = 20 \text{ A},$	-	1.75		V
W	Diada farward valtaga	$V_{IN}^{(1)} = 0$ , $I_C = 15 \text{ A}$	-	1.7	2.4	.,
V <sub>F</sub>	Diode forward voltage	$V_{IN}^{(1)} = 0, I_C = 20 A$	-	1.8		V
Inductive	e load switching time a	and energy <sup>(2)</sup>		!		!
t <sub>on</sub>	Turn-on time		-	320		
t <sub>c(on)</sub>	Cross-over time on		-	160		
t <sub>off</sub>	Turn-off time		-	510		ne
t <sub>c(off)</sub>	Cross-over time off		-	102		ns
t <sub>rr</sub>	Reverse recovery time	$V_{DD} = 300 \text{ V}, V_{CC} = V_{boot} = 15 \text{ V},$	-	290		
E <sub>on</sub>	Turn-on switching loss	$V_{IN}^{(1)} = 0 \text{ to 5 V, I}_{C} = 15 \text{ A}$	-	440		
E <sub>off</sub>	Turn-off switching loss		-	213		μJ
E <sub>rr</sub>	Reverse recovery energy loss			59		
t <sub>on</sub>	Turn-on time		-	338		
t <sub>c(on)</sub>	Cross-over time on		-	178		
t <sub>off</sub>	Turn-off time		-	500		ne
t <sub>c(off)</sub>	Cross-over time off		-	92		ns
t <sub>rr</sub>	Reverse recovery time	$V_{DD} = 300 \text{ V}, V_{CC} = V_{boot} = 15 \text{ V},$	-	300		
E <sub>on</sub>	Turn-on switching loss	$V_{IN}^{(1)} = 0 \text{ to 5 V, } I_C = 20 \text{ A}$		624		
E <sub>off</sub>	Turn-off switching loss		-	296		μJ
E <sub>rr</sub>	Reverse recovery energy loss			80		

<sup>1.</sup> Applied between HINx, LINx and GND for x = U, V, W

t<sub>on</sub> and t<sub>off</sub> include the propagation delay time of the internal drive. t<sub>C(on)</sub> and t<sub>C(off)</sub> are the switching time of IGBT itself under the internally given gate driving condition.



Electrical characteristics STGIB15CH60TS-E

Ic Vcc 🗀 VCC воот HIN GND OUT <u></u>

− Vdd Input VCC LIN Rsd Vce +5V [  $\overline{\mathrm{SD}}$ LVG CIN GND

Figure 2. Switching time test circuit



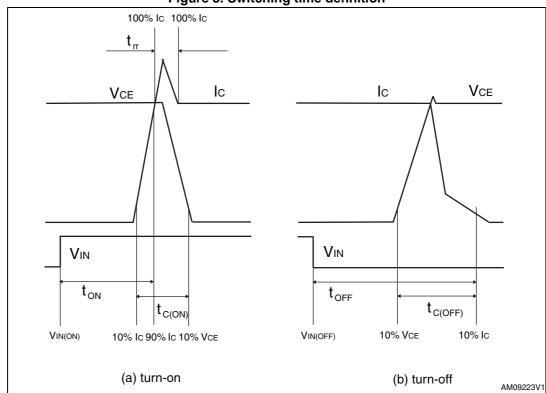


Table 8. Control / protection parts

Symbol	Parameter	Test condition	Min	Тур	Max	Unit
$V_{il}$	Low logic level voltage				0.8	V
V <sub>ih</sub>	High logic level voltage		2			V
I <sub>INh</sub>	IN logic "1" input bias current	IN <sub>x</sub> =15V	80	150	200	μA
I <sub>INI</sub>	IN logic "0" input bias current	IN <sub>x</sub> =0V			1	μA
High side						
V <sub>CC_hys</sub>	V <sub>CC</sub> UV hysteresis		1.2	1.4	1.7	V
V <sub>CCH_th(on)</sub>	V <sub>CCH</sub> UV turn-on threshold		11	11.5	12	V
V <sub>CCH_th(off)</sub>	V <sub>CCH</sub> UV turn-off threshold		9.6	10.1	10.6	V
V <sub>BS_hys</sub>	V <sub>BS</sub> UV hysteresis		0.5	1	1.6	V
V <sub>BS_th(on)</sub>	V <sub>BS</sub> UV turn-on threshold		10.1	11	11.9	V
V <sub>BS_th(off)</sub>	V <sub>BS</sub> UV turn-off threshold		9.1	10	10.9	V
I <sub>QBSU</sub>	Under voltage V <sub>BS</sub> quiescent current	$V_{BS} = 9 \text{ V, HINx}^{(1)} = 5 \text{V;}$		55	75	μA
I <sub>QBS</sub>	V <sub>BS</sub> quiescent current	V <sub>CC</sub> = 15 V, HINx <sup>(1)</sup> = 5V		125	170	μA
I <sub>qccu</sub>	Under voltage quiescent supply current	V <sub>CC</sub> = 9 V, HINx <sup>(1)</sup> = 0		190	250	μA
I <sub>qcc</sub>	Quiescent current	$V_{CC} = 15 \text{ V, HINx}^{(1)} = 0$		560	730	μA
R <sub>DS(on)</sub>	BS driver ON resistance			150		Ω
Low side			•			
V <sub>CC_hys</sub>	V <sub>CC</sub> UV hysteresis		1.1	1.4	1.6	V
V <sub>CCL_th(on)</sub>	V <sub>CCL</sub> UV turn-on threshold		10.4	11.6	12.4	V
V <sub>CCL_th(off)</sub>	V <sub>CCL</sub> UV turn-off threshold		9.0	10.3	11	V
I <sub>qccu</sub>	Under voltage quiescent supply current	$V_{CC} = 10 \text{ V}, \overline{SD} \text{ pulled to}$ 5V through $R_{SD} = 10k\Omega$ , $CIN = LINx^{1} = 0$ ;		600	800	μA
I <sub>qcc</sub>	Quiescent current	$V_{CC} = 15 \text{ V}, \overline{SD} = 5\text{V},$ $CIN = LINx^{1)} = 0;$		700	900	μΑ
V <sub>SSD</sub>	Smart SD unlatch threshold		0.5	0.6	0.75	٧
I <sub>SDh</sub>	SD logic "1" input bias current	<del>SD</del> = 5V	25	50	70	μA
I <sub>SDI</sub>	SD logic "0" input bias current	SD =0V			1	μΑ

Electrical characteristics STGIB15CH60TS-E

Table 8. Control / protection parts (continued)

Symbol	Parameter	Test condition	Min	Тур	Max	Unit	
Temperature	Temperature sensor output						
V <sub>TSO</sub>	Temperature sensor output voltage	T <sub>j</sub> = 25 °C		1.15		V	
I <sub>TSO_SNK</sub>	Temperature sensor sink current capability			0.1		mA	
I <sub>TSO_SRC</sub>	Temperature sensor source current capability		4			mA	

<sup>1.</sup> Applied between HINx, LINx and GND for x = U, V, W

Table 9. Sense comparator ( $V_{CC} = 15 \text{ V}$ , unless otherwise is specified)

Symbol	Parameter	Test condition	Min	Тур	Max	Unit
I <sub>CIN</sub>	CIN input bias current	V <sub>CIN</sub> =1V	-0.2		0.2	μΑ
V <sub>ref</sub>	Internal reference voltage		460	510	560	mV
V <sub>OD</sub>	Open drain low level output voltage	I <sub>od</sub> = 5mA			500	mV
t <sub>CIN_SD</sub>	C <sub>IN</sub> comparator delay to SD	SD pulled to 5V through R <sub>SD</sub> =10kΩ; measured applying a voltage step 0-1V to Pin CIN 50% CIN to 90% SD	240	320	410	ns
SR <sub>SD</sub>	SD fall slew rate	$\overline{\text{SD}}$ pulled to 5V through R <sub>SD</sub> =10k $\Omega$ ; C <sub>L</sub> =1nF through $\overline{\text{SD}}$ and ground; 90% $\overline{\text{SD}}$ to 10% $\overline{\text{SD}}$		25		V/µs

Note: Comparator remains enabled even if  $V_{CC}$  is in UVLO condition but higher than 4 V.

STGIB15CH60TS-E **Fault management** 

#### **Fault management** 4

The device integrates an open-drain output connected to SD Pin. As soon as a fault occurs, the open-drain is activated and LVGx outputs are forced low. Two types of fault can be detected:

- Overcurrent (OC) sensed by the internal comparator (see more detail in Section 4.2: Smart shutdown function);
- Undervoltage on supply voltage (V<sub>CC</sub>);

Each fault enables the SD open drain for a different time; refer to the following *Table 10:* Fault timing.

Table 1011 aut mining							
Symbol	Parameter	Event time	SD open-drain enable time result				
ОС	Overcurrent event	≤ 20 µs	20 µs				
	Overcurrent event	≥ 20 µs	OC time				
		≤ 50 µs	50 µs				
UVLO	Undervoltage lock out event	≥ 50µs  until the VCC_LS exceed the VCC_LS UV turn ON threshold	UVLO time				

Table 10. Fault timing

The device actually remains in a fault condition (SD at low logic level and LVGx outputs disabled) for a time that also depends on the RC network connected to the SD pin. The network generates a time interval that is added to the internal value.

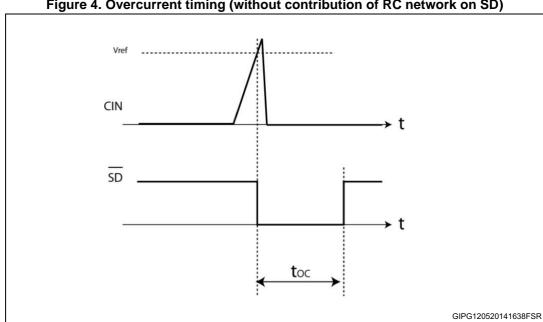


Figure 4. Overcurrent timing (without contribution of RC network on SD)

Fault management STGIB15CH60TS-E

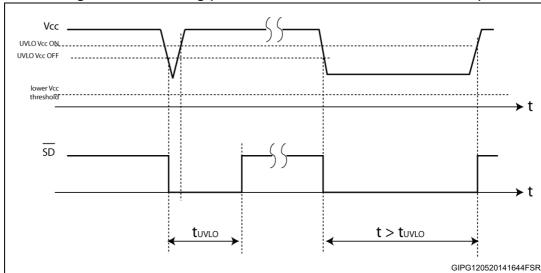


Figure 5. UVLO timing (without contribution of RC network on SD)

### 4.1 TSO output

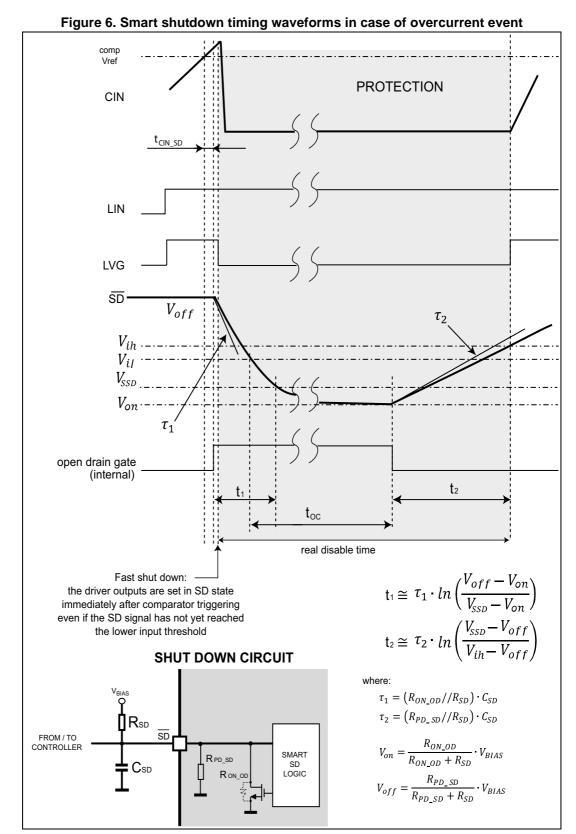
The device integrates a temperature sensor. A voltage proportional to die temperature is available on the TSO pin. When this function is not used, the pin can be left floating.

#### 4.2 Smart shutdown function

The device integrates a comparator committed to the fault sensing function. The comparator input can be connected to an external shunt resistor in order to implement a simple overcurrent detection function.

The output signal of the comparator is fed to an integrated MOSFET with the open drain output available on SD input. When the comparator triggers, the device is set in the shutdown state and its outputs are all set to low level.

STGIB15CH60TS-E Fault management



Note:  $R_{ON\_OD} = V_{OD}/5 \text{ mA see Table 9; } R_{PD\_SD} \text{ (typ)} = 5 \text{ V/I}_{SDh}$ 



Fault management STGIB15CH60TS-E

In common over-<u>current</u> protection architectures, the comparator <u>output</u> is usually connected to the <u>SD</u> input and an RC network is connected to this <u>SD</u> line in order to provide a mono-stable circuit, which implements a protection time that follows the fault condition.

Differently from the common fault detection systems, the device Smart shutdown architecture allows to immediately turn-off the outputs gate driver in case of fault, by minimizing the propagation delay between the fault detection event and the actual outputs switch-off. In fact the time delay between the fault and the outputs turn off is no more dependent on the RC value of the external network connected to the pin.

In the smart shutdown circuitry, the fault signal has a preferential path which directly switches off the outputs after the comparator triggering.

At the same time the internal logic turns on the open drain output and holds it on until the  $\overline{SD}$  voltage goes below the  $V_{SSD}$  threshold and  $t_{oc}$  time is elapsed.

The driver outputs restart following the input pins as soon as the voltage at the  $\overline{SD}$  pin reaches the higher threshold of the  $\overline{SD}$  logic input.

The Smart shutdown system provides the possibility to increase the time constant of the external RC network (that is the disable time after the fault event) up to very large values without increasing the delay time of the protection.

# 5 Typical application circuit

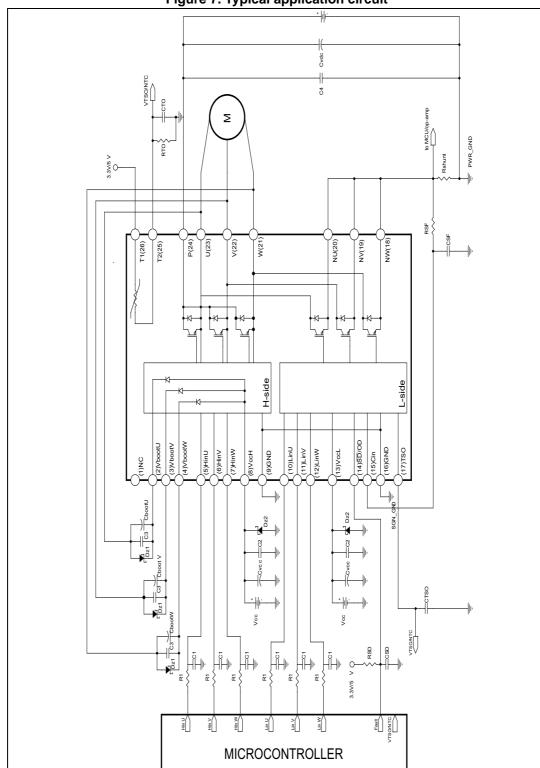


Figure 7. Typical application circuit

Recommendations STGIB15CH60TS-E

### 6 Recommendations

1. Input signals HIN, LIN are active-high logic. A 500 k $\Omega$  (typ.) pull-down resistor is built-in for each high side input. To prevent input signal oscillation, the wiring of each input should be as short as possible and the use of RC filters (R1, C1) on each input signal is suggested. The filters should be done with a time constant of about 100 ns and must be placed as close as possible to the IPM input pins.

- 2. The bypass capacitor Cvcc (aluminum or tantalum) is recommended to reduce the transient circuit demand on the power supply. In addition, a decoupling capacitor C<sub>2</sub> (100 to 220 nF, with low ESR and low ESL) is suggested, to reduce high frequency switching noise distributed on the power supply lines. It must be placed as close as possible to each Vcc pin and in parallel to the bypass capacitor.
- 3. The use of RC filter (RSF, CSF) for preventing protection circuit malfunction is recommended. The time constant (RSF x CSF) should be set to 1us and the filter must be placed as close as possible to the CIN pin.
- 4. The  $\overline{SD}$  is an input/output pin (open drain type if used as output). It should be pulled up to MCU power supply (3.3/5 V) by a resistor higher than 1.0 k $\Omega$  in order to keep  $I_{od}$  lower than 5 mA. The filter on  $\overline{SD}$  has to be sized to  $\underline{get}$  a desired re-starting time after a fault event and placed as close as possible to the  $\overline{SD}$  pin.
- 5. To increase the noise immunity of the TSO thermal sensor, it is recommended to parallel a decoupling capacitor  $C_{TSO}$  between 1 nF and 10 nF. Similarly, if the NTC thermistor is available and used, it is recommended to parallel a decoupling capacitor  $C_{OT}$  between 10 nF and 100 nF. In both cases, the capacitors must be placed close to the MCU.
- 6. The decoupling capacitor C<sub>3</sub> (100 to 220 nF, with low ESR and low ESL) in parallel with each C<sub>boot</sub> is recommended to filter high frequency disturbances. Both C<sub>boot</sub> and C<sub>3</sub> must be placed as close as possible to the U,V,W and V<sub>boot</sub> pins. Bootstrap negative electrodes should be connected to U,V,W terminals directly and separated from the main output wires.
- A Zener diode (Dz1) between each V<sub>cc</sub> pin and GND, and in parallel (Dz2) with each Cboot is suggested in order to prevent overvoltage.
- The decoupling capacitor C<sub>4</sub> (100 to 220 nF, with low ESR and low ESL) in parallel with the electrolytic capacitor Cvdc is recommended, in order to prevent surge destruction. Both capacitors C<sub>4</sub> and Cvdc should be placed as close as possible to the IPM (C<sub>4</sub> has priority over Cvdc).
- 9. By integrating an application-specific type HVIC inside the module, direct coupling to the MCU terminals without an opto-coupler is possible.
- 10. Low inductance shunt resistors should be used for phase leg current sensing
- 11. In order to avoid malfunctions, the wiring between N pins, the shunt resistor and PWR\_GND should be as short as possible.
- 12. It is recommended to connect SGN\_GND to PWR\_GND at only one point (near the terminal of shunt resistor), in order to avoid any malfunction due to power ground fluctuation.

STGIB15CH60TS-E Recommendations

Table 11. Recommended operating conditions

Symbol	Parameter	Test condition	Min	Тур	Max	Unit
V <sub>PN</sub>	Supply voltage	Applied between P-Nu, N <sub>V</sub> , N <sub>w</sub>		300	400	V
V <sub>CC</sub>	Control supply voltage	Applied between V <sub>CC</sub> -GND	13.5	15	18	٧
V <sub>BS</sub>	High side bias voltage	Applied between V <sub>BOOTi</sub> -OUT <sub>i</sub> for i = U, V, W	13		18	V
t <sub>dead</sub>	Blanking time to prevent Arm-short	For each input signal	1.0			μs
f <sub>PWM</sub>	PWM input signal	-40 °C < T <sub>C</sub> < 100 °C -40 °C < T <sub>j</sub> < 125 °C			20	kHz
T <sub>C</sub>	Case operation temperature				100	°C

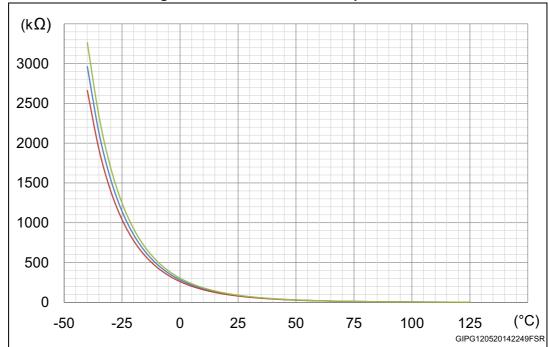
NTC thermistor STGIB15CH60TS-E

### 7 NTC thermistor

Table 12. NTC thermistor

Symbol	Parameter	Test condition	Min	Тур	Max	Unit
R <sub>25</sub>	Resistance	T = 25 °C		85	-	kΩ
R <sub>125</sub>	Resistance	T = 125 °C		2.6	-	kΩ
В	B-constant	T = 25 to 100 °C		4092		K
Т	Operating temperature range		-40		125	°C

Figure 8. NTC resistance vs. temperature



STGIB15CH60TS-E NTC thermistor

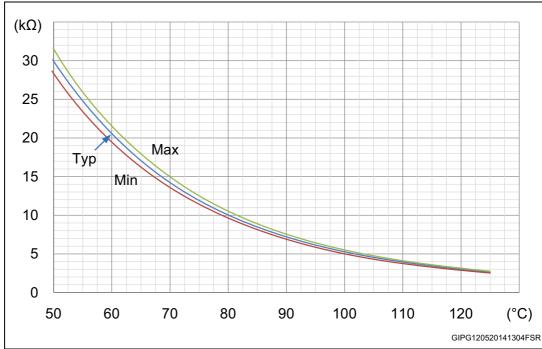
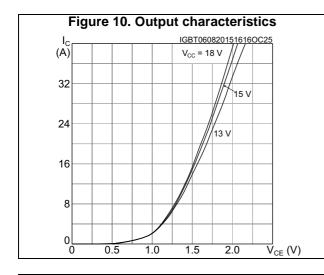
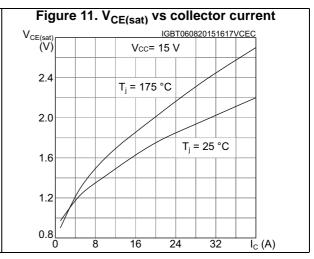
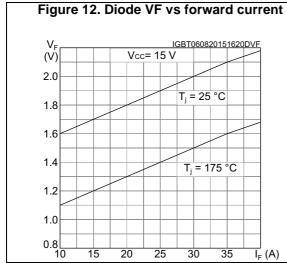


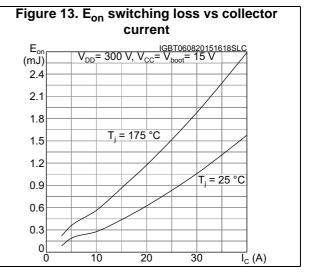
Figure 9. NTC resistance vs. temperature - zoom

## 8 Electrical characteristics (curves)







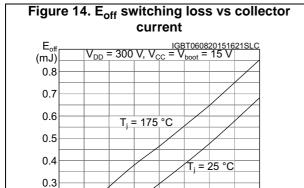


0.2

0.1

0 0

10

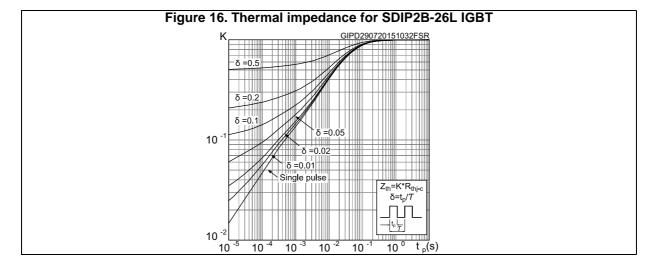


20

30

 $\overline{I}_{C}(A)$ 

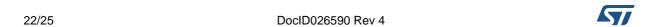
Figure 15. VTSO output characteristics vs LVIC temperature IGBT060820151621VTSO 3.0 2.7 2.4 2.1 1.8 1.5 1.2 0.9 0.6L 0 T<sub>C</sub> (°C) 25 50 75 100



Package information STGIB15CH60TS-E

## 9 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.



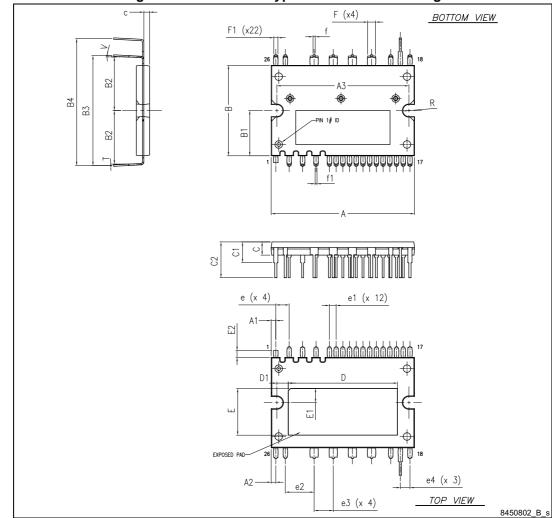


Figure 17. SDIP2B-26L type E mechanical drawing

Table 13. SDIP2B-26L type E mechanical dimensions<sup>(1)</sup>

Ref.	Dimensions	Ref.	Dimensions	Ref.	Dimensions	
Α	$38.00 \pm 0.50$	С	3.50 ± 0.20	Е	12.40 ± 0.50	
A1	1.22 ± 0.25	C1	5.50 ± 0.50	E1	$3.75 \pm 0.30$	
A2	1.22 ± 0.25	C2	9.50 ± 0.50	E2	1.80	
А3	35.00 ± 0.30	е	3.556 ± 0.200	f	0.60 ± 0.15	
С	1.50 ± 0.05	e1	1.778 ± 0.200	f1	0.50 ± 0.15	
В	24.00 ± 0.50	e2	7.62 ± 0.20	F	2.10 ± 0.15	
B1	12.00	e3	5.08 ± 0.20	F1	1.10 ± 0.15	
B2	14.40 ± 0.50	e4	2.54 ± 0.20	R	1.60 ± 0.20	
В3	29.20 ± 0.50	D	28.95 ± 0.50	Т	0.400 ± 0.025	
B4	$33.70 \pm 0.50$	D1	3.025 ± 0.300	V	0° / 5°	

<sup>1.</sup> All dimensions are expressed in millimeters.

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# 10 Revision history

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**Table 14. Document revision history** 

Date	Revision	Changes
23-Jun-2014	1	Initial release.
27-Aug-2014	2	Updated Table 1: Device summary.
03-Sep-2015	3	Text and formatting changes throughout document On cover page: - updated Title, Features and Description In Section 1: Internal schematic and pin description: - updated Figure 1 and Table 2 In Section 2: Absolute maximum ratings: - updated Table 3, Table 4, Table 5 and Table 6 In Section 3: Electrical characteristics: - updated Table 7, Figure 2, Table 8 and Table 9 In Section 4: Fault management: - updated Figure 6 In Section 5: Typical application circuit: - updated Figure 7 In Section 6: Recommendations: - updated recommendations list and added Table 11 In Section 8: Electrical characteristics (curves): - added Figure 10, Figure 11, Figure 12, Figure 13, Figure 14, Figure 15 and Figure 16 Minor text changes
07-Sep-2015	4	Datasheet promoted from preliminary data to production data

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